UNIVERSITY OF CALIFORNIA, BERKELEY College of Engineering Department of Electrical Engineering and Computer Sciences

EE 105: Microelectronic Devices and Circuits

Fall 2011

MIDTERM EXAMINATION

Ti	me allotted: 60 minutes
	Solution
NAME:	
STUDENT ID#:	·
INSTRUCTIONS:	
 Unless otherwise stated a. temperature is 30 b. material is Si c. No Early effect 	·
Specially, while us have got your num	. (Make your methods clear to the grader!) sing chart, make sure that you indicate how you abers. For example, if reading off mobility, clearly loping density that corresponds to.
3. Clearly mark (underlin	ne or box) your answers.
4. Specify the units on ans	swers whenever appropriate.
SCORE	:1/20
SCORE	2:1/20 2/20

_____/60

Total

PHYSICAL CONSTANTS

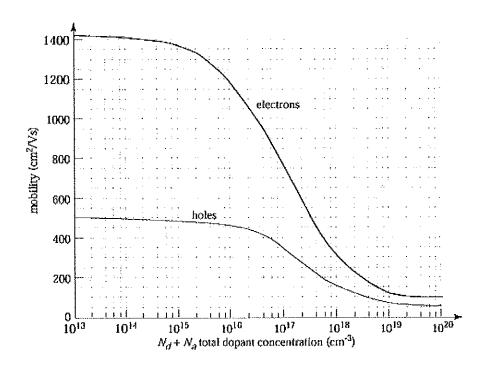
<u>Description</u>	Symbol	<u>Value</u>	PROPERTIES OF	SILICON A	AT 300K
Electronic charge	q	1.6×10 ⁻¹⁹ C	<u>Description</u>	<u>Symbol</u>	<u>Value</u>
Boltzmann's constant	k	8.62×10^{-5}	Band gap energy	$E_{ m G}$	1.12 eV
		eV/K	Intrinsic carrier	$n_{\rm i}$	$10^{10} \mathrm{cm}^{-3}$
Thermal voltage at	$V_{\mathrm{T}} =$	0.026 V	concentration		10
300K	kT/q		Dielectric permittivity	$arepsilon_{ ext{Si}}$	1.0×10^{-12}
	4				F/cm

USEFUL NUMBERS

 $V_{\rm T} \ln(10) = 0.060 \text{ V} \text{ at } T=300 \text{K}$

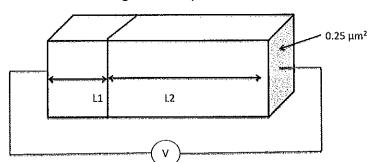
Depletion region Width:
$$W = \sqrt{\frac{2\varepsilon}{q} \left(\frac{1}{N_a} + \frac{1}{N_d} \right) (V_{bi} - V_{Applied})}$$

Electron and Hole Mobilities in Silicon at 300K



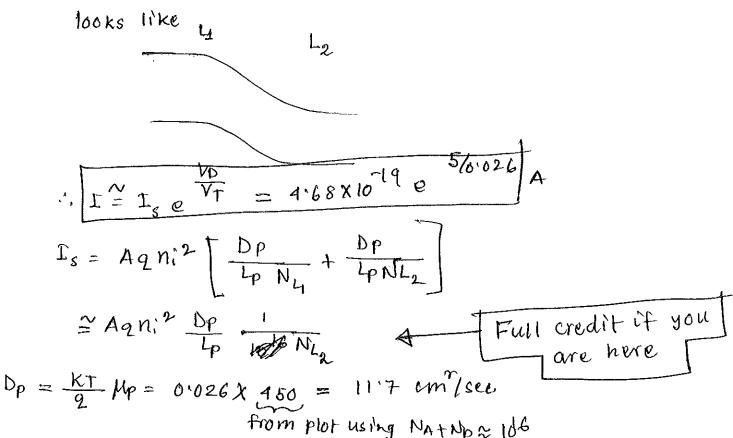
Prob 1. [20]

(a) [10 pts] Consider a Si slab as shown below. The slab has been doped with two different concentrations of acceptor ions 10^{18} /cm³ and 10^{16} /cm³ respectively in region L1 and L2 as shown in the figure. L1=10 μ m and L2=30 μ m. If a voltage of 5V is applied across the sample as shown in the figure, approximately calculate the current flowing in the sample. The cross sectional area of the sample is 0.25 μ m².



Two regions have two different hole density. Therefore diffusion will happen in equilibrium and a junction will form.

Li region loses a lot more holes; so energy band diagram looks like.



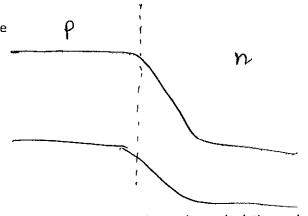
Assume $L_{p} \ll 4 \, \text{E} \, L_{2}$; Take $L_{p} \sim 1 \, \mu \text{m}$ (see hw2, prob 3) $L_{s} = 0.25 \times 10^{8} \times 1^{16} \times 10^{19} \times 10^{20} \times \frac{11^{77}}{10^{4}} \cdot \frac{1}{10^{16}} = 4.68 \times 10^{19} \text{A}$



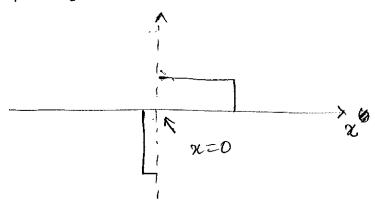
(b) [10 pts] (each question is worth 2 points) Consider a diode shown below:

N _A =10 ¹⁸ cm ⁻³	N _D =10 ¹⁶ cm ⁻³

(i) Draw the energy band profile



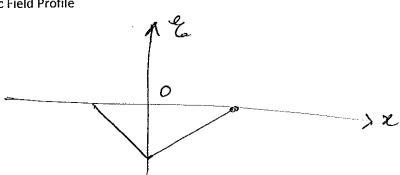
(ii) Draw the profile of the depletion region. You can make an abrupt depletion region approximation.



WXI

so higher doped region mas smaller depletion width.





n

P

(iV) Calculate the built in voltage.

$$V_{bi} = \frac{KT}{2} In \frac{NA-ND}{n_{i}^{2} 2}$$

$$= \frac{KT}{2} In \frac{10^{34}}{10^{20}} = 14 \times 60 \text{ mV}$$

$$= 840 \text{ mV}$$

(V) Calculate the depletion width

$$W = \sqrt{\frac{28si}{9} \left(\frac{1}{NA} + \frac{1}{Nb}\right) V_{bi}}$$

$$\frac{N}{2} \sqrt{\frac{2\times10^{12}}{1.6\times10^{19}}} \frac{1}{Nb} \times 0.84$$

$$\frac{2\times10^{12}}{1.6\times10^{19}} \times \frac{1}{10^{16}} \times 0.84$$

$$\frac{2\times10^{12}}{1.6\times10^{19}} \times \frac{1}{10^{16}} \times 0.84$$

$$\frac{2\times10^{12}}{1.6\times10^{19}} \times \frac{1}{10^{16}} \times 0.84$$

$$W = 2.89 \times 10^{5} \text{ cm}$$

Prob 2. [20 pts]

(a) [7 pts] Consider two diodes:

D1: $N_A = 10^{18}$ and $N_D = 10^{16}$ /cm³ and

D2: $N_D = 10^{18}$ and $N_A = 10^{16} / cm^3$

If both diodes are forward biased with the same amount of voltage, do you expect a difference in the current for the two diodes? Why or Why not? Clearly justify your answer.

For DI: current is dominated by holes

Da: current is dominated by electrons

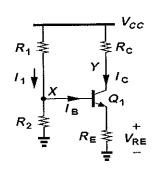
since for the same density

un> up

(b)[3 pts] Please use one of the three options (i) increases (ii) decreases or (iii) no change to fill out the following table. When considering one parameter change, assume everything else is kept fixed.

Parameter	Early Voltage	β	
Increase width of the base	decreases	decreases	
Increase emitter Doping	no change	increases	
Increase collector doping	decreases	no change	

(c) [10 pts]



For the circuit shown above, it is known that V_{cc} =5V, β =100, I_s =10⁻¹⁴ A and the desired I_c = 1 mA. Choose the values of R_c , R_E , R_1 and R_2 that makes sure that the transistor is in forward active region. Clearly write down all the approximations that you are making.

$$I_{e} = I_{s} e$$

$$V_{BE} = V_{T} \ln \frac{I_{c}}{I_{s}}$$

$$= \frac{k_{T}}{q} \ln \frac{10^{-3}}{15^{14}}$$

$$= 660 \text{ mV}$$

$$V_{RE} \cong 1V$$

$$V_{CE} = 5V - 1V - 1V$$

$$= 3V$$

$$V_X = V_{BE} + V_{RE}$$

$$= 1.66 V$$

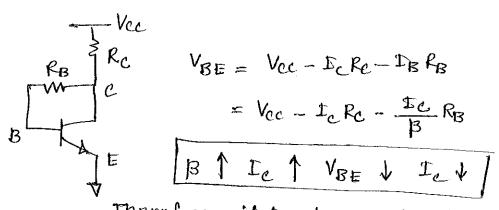
$$E_1 = 100 \times \frac{EC}{B} = 10^{-3} A$$

1.
$$R_2 = \frac{1.67 \text{ V}}{10^3 \text{ A}} = 1.67 \text{ KD}$$

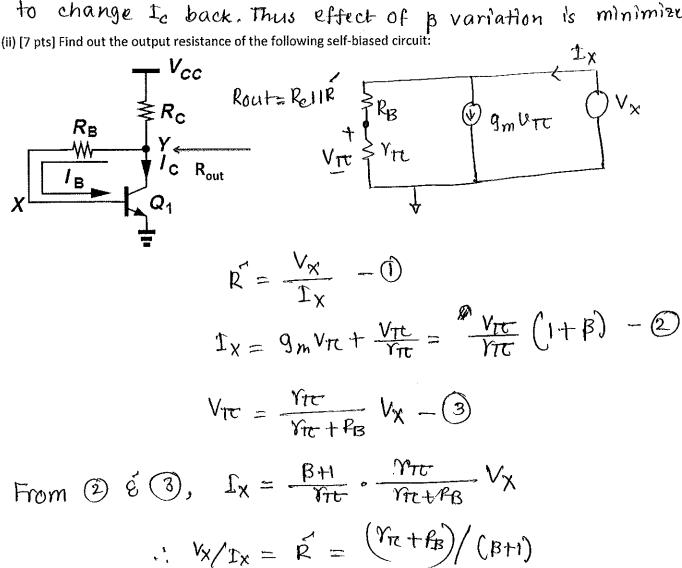
$$R = \frac{(5-1.67)V}{10.3 \text{ A}} = 3.33 \text{ KD}$$

Prob 3 [20 pts]

- (a) [10 pts]
- (i) [3 pts] Explain how a self-biased circuit helps improve the tolerance to variation in β .

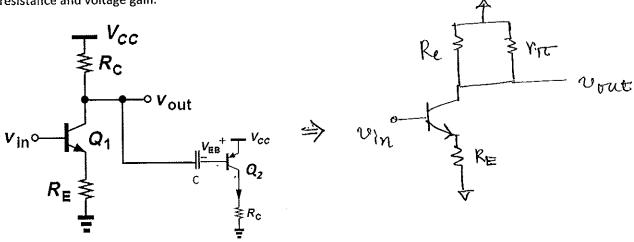


Therefore, if Ic changes due to change in B, VBE changes to change Ic back. Thus effect of B variation is minimized.



: Rout = (Re 11 YIZ+ PB)

(b) [10 pts] For the following amplifier circuit, find out the expressions for input resistance, output resistance and voltage gain.



Rin =
$$r_{r_i}$$
+ $(\beta+1)$ RE

Rout = R_c 11 r_{r_i} 2

Av $\frac{\alpha}{r_i}$ - $\frac{R_c}{1/g_m}$ + R_E

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